



**INTERNATIONAL STANDARD ISO/IEC 10373-3:2010**  
**TECHNICAL CORRIGENDUM 1**

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## **Identification cards — Test methods —**

**Part 3:**

### **Integrated circuit cards with contacts and related interface devices**

TECHNICAL CORRIGENDUM 1:

*Cartes d'identification — Méthodes d'essai —*

*Partie 3: Cartes à circuit(s) intégré(s) à contacts et dispositifs d'interface assimilés*

*RECTIFICATIF TECHNIQUE 1:*

Technical Corrigendum 1 to ISO/IEC 10373-3:2010 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

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#### **4.7.2.14 NOTE**

Replace the note with

“If a specific functionality is not implemented in the IFD, the IFD-test-apparatus is not required to have the corresponding test-capability (e.g. T=1 protocol not implemented in the IFD)”

5.1.2 Step e)

Replace

“ISO/IEC 7816-3:2006, 5.3.4”

with

“ISO/IEC 7816-3:2006, 6.3.2”.

6.2.2.2 step a)

Replace

“Run the Test Scenario with the card with nominal bit-timing parameters (see ISO/IEC 7816-3:2006,10.2)”

with

“Run the Test Scenario with the card with nominal character-timing parameters (see ISO/IEC 7816-3:2006,7.2)”

6.2.3.2 step d)

Replace

“Repeat a) to b) with every provided etu-factor”

with

“Repeat a) to c) with every provided etu-factor”.

8.2.3.2 step e)

Replace

“card-test-apparatus”

with

“IFD-test-apparatus”.

*Table 68 - Title*

Replace

“card test apparatus bit timing parameters”

with

“IFD test apparatus bit timing parameters”

8.3.2.2 step c)

Replace

“Repeat a) with every provided etu-factor”

with

“Repeat a) to b) with every provided etu-factor”.

8.3.2.2 step d)

Replace

“card-test-apparatus”

with

“IFD-test-apparatus”.

Table 70 - Title

Replace

“card test apparatus bit timing parameters”

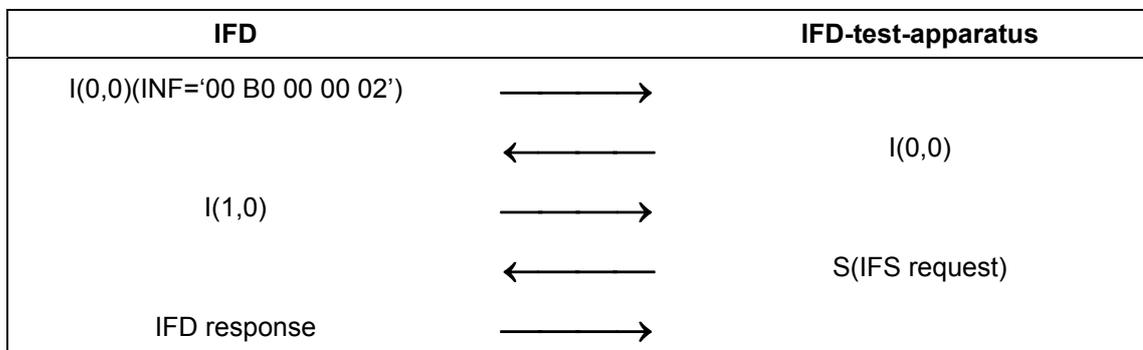
with

“IFD-test-apparatus bit timing parameters”

8.3.9.2 Scenario 20 and 21

Insert new Scenario 20

**Scenario 20 — IFD – Reaction of the IFD to receive S(IFS request)**



Renumber existing Scenario 20 to Scenario 21

Renumber existing Scenario 21 to Scenario 22